Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/618,850	TANAKA ET AL.	
Examiner	Art Unit	
David Nhu	2818	

	SEARCHED				
Cla	ass	Subclass	Date	Examiner	
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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SEARCHED IN EAST	6/12/2006	DN		